Special Issue

Advances in Wireless Communications Using Machine Learning and Deep Learning Techniques

Message from the Guest Editor

Artificial intelligence (AI) is a growing technology capable of performing complex tasks similarly to human behavior. Machine learning (ML) and deep learning (DL) are the two main conceptualization portions of AI. ML and DL are becoming part of new wireless communications curricula due to the necessity to solve the increased challenges in wireless communications and networks. The development of ML and DL technologies for wireless communication has expanded intensely due to the growth of the unique demands and applications in wireless communications requiring more intelligent operations and processing. As a result, ML and DL have become one of the most important trends in wireless communications research and applications. This Special Issue aims to combine the research results and industrial applications of ML and DL for wireless communications and networks.

Guest Editor

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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